

ETX-LN

Temperature/Humidity Test Report

Report NO: 11E020005

Summary	<p><input checked="" type="checkbox"/> Pass</p> <p><input type="checkbox"/> Fail</p> <p>Note : There is/are ___ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> Pass with Deviation</p> <p>Comment: _____</p>
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Issue date

2011-2-14

Approval

Jansin Lee

Test Engineer

Allen Hsu

Test item list

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Testing Result

Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Temperature variation operation test	Pass	
3	Cold start and hot start test	Pass	

Configuration of EUT

Test Product: ETX-LN A0.2

Sample Configuration & Quantity Under Test:

1. M/B Board: ETX-LN A0.2
2. CPU: Intel(R) Atom CPU D525 1.8GHz (Bios Ver.0.48)
3. Chipset: Intel Host Bridge / Intel ICH8M
4. VGA: Internal Intel Graphics Media Accelerator 3150
5. Memory: Team 2GB / hynix H5TQ2G83AFR-H9C / DDR3 1333
6. SSD: PATA - SST SSD 4G – SST85LD1004T-60-RI-LCTE
7. Test Software: Windows XP / Run PassMark Burn In Test Pro 6.0-1026
8. ATX Power: Delta ATX Power 350W GPS-350EB-102A
9. Heat Sink:



Temp./humidity power on/off test

Test Date: 01-25~01/26 -2011

Test Site: AAEON Internal Lab.

Test Standard: Reference IEC 68-2-30 Testing procedures

Test Db: Damp Heat Test

Test Equipment:

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

Model: THS-D4H+-100

Date of Calibration: 2010-04-01

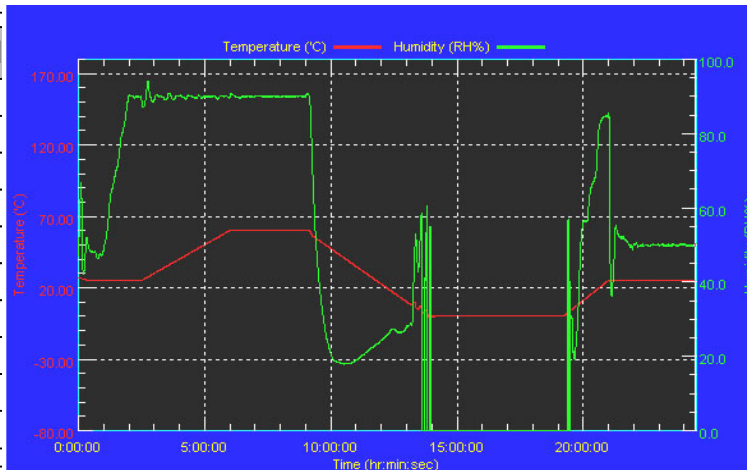
Serial Number: 2582

Temperature & Humidity Power On/Off Test:

Testing Specification:

Step	Temperature (°C)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

Test Curve:



Test Result:

Power on/off test:

Test Method	Actual	Successful	Failure rate
Power On/Off	1086/times	1086/times	0 %
Note: Failure rate need to under 0.2%.			

Temperature variation operation test

Test Date: 01-27~01-28-2011

Test Site: AAEON Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

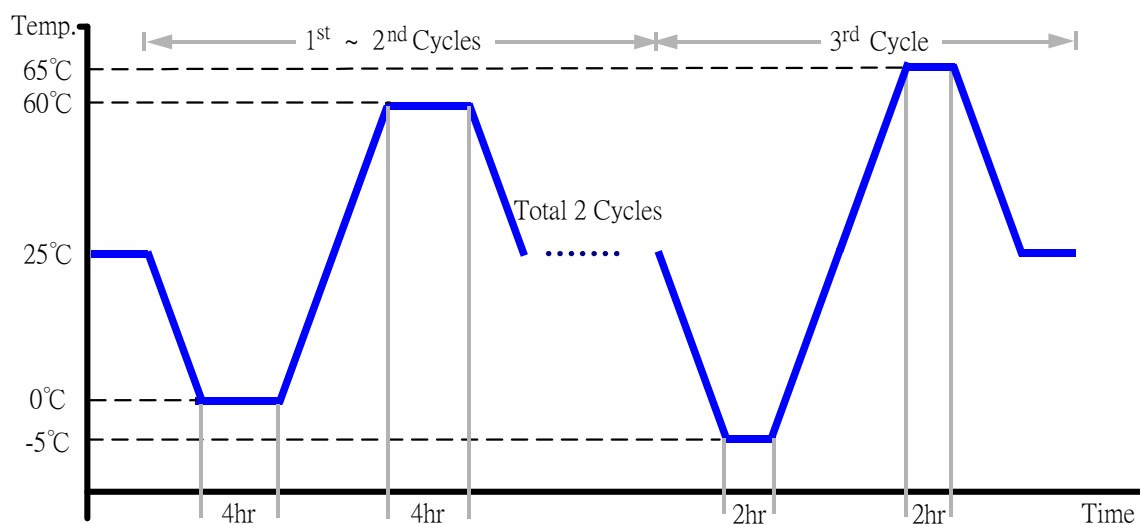
Model: THS-D4H+-100

Date of Calibration: 2010-04-01

Serial Number: 2582

Temperature & Humidity Cycle Test:

1. Test Low Temperature: 0°C (1~2 cycles)
-5°C (3rd cycle)
2. Test High Temperature: 60°C (1~2 cycles)
65°C (3rd cycle)
3. Test dwell time: 4Hrs (1~2 cycles)
2Hrs (3rd cycle)
4. Temperature slope: 2°C/min
5. Test cycle: 3 cycles
6. Test Environment Curve:



Test Result:

No problem was found during the temperature variation operation test.

Cold start and hot start test

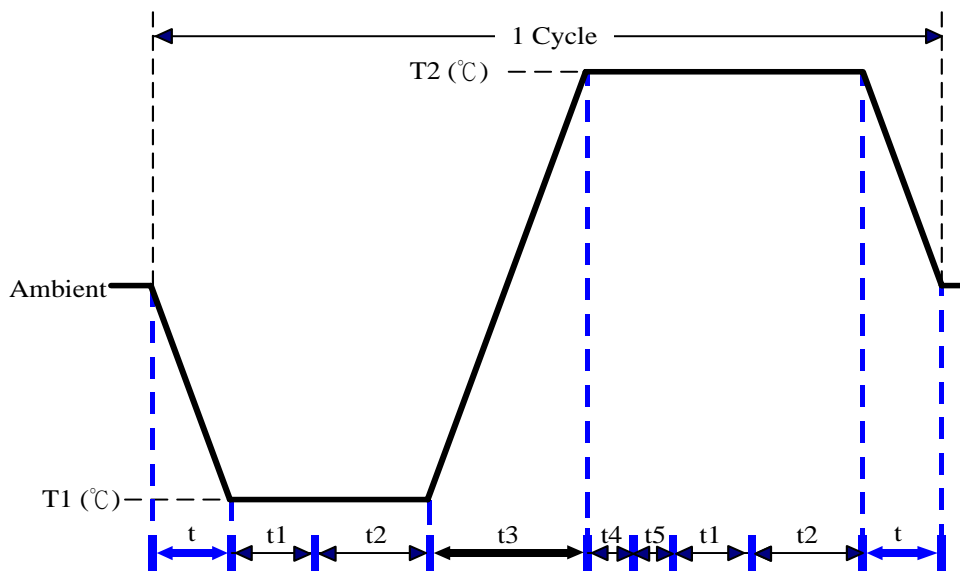
Test Date: 2/8~2/9 -2011

Test Site: AAEON Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 2010-04-01
Serial Number: 2582

Test Condition:



Parameters	Description
T1	-5°C
T2	65°C
t1	1 hrs
t2	2 hrs
t4, t5	30 min
t, t3	2°C/min
n (Cycle)	1

t,t3 = temprature slope
t, t1: Power Off
t2: Power on/off test 10 times (on 2 min / off 5min)
t3,t4: Run PassMark Burn In Test
t5: Win XP Software restart test 2 times
Test Software:Windows XP

Test Result:

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.